



## ***Acta IMEKO Special Issue: Measurements in Cultural Heritage***



### **Call for papers**

The IMEKO TC-24 on Chemical Measurements promotes a new Special Issue in Acta IMEKO related to '*Measurements in Cultural Heritage*'. The fields of characterisation, valorisation, and preservation of Cultural Heritage (CH) are deeply connected to the metrological issues related to the collection, interpretation, and validation of data acquired using different analytical, physical-chemical, mechanical and imaging techniques.

Aim of this Special Issue is to publish research papers related, but not limited to, the following topics:

- Archaeometry
- Chemical and thermal analyses for CH
- Digital survey methodologies
- IoT-based systems for CH monitoring
- Diagnosis and monitoring for the restoration, preventive conservation, and maintenance of CH.
- Instrumentation for CH
- Geomatics
- Imaging techniques for CH
- Non-invasive and on-site measurements

All manuscripts will undergo the journal peer-review process. In the Cover Letter, please specify that your paper is submitted to the Special Issue '*Measurements in Cultural Heritage*'. Additional information about the manuscript submission process can be found in Acta IMEKO website: <https://acta.imeko.org/index.php/acta-imeko/about/submissions>

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#### **Important dates**

**15<sup>th</sup> April 2022**



**September 2022**

**NEW DEADLINE for manuscript submission**

Publication in Acta IMEKO

#### **Authors benefits**

- **Open Access (after publication the articles will be freely available for all readers)**
- **No publication fees for Authors**
- **Indexed in Scopus and DOAJ**
- **Fast peer-review process**